



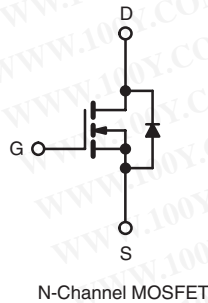
勝特力材料 886-3-5753170  
 勝特力电子(上海) 86-21-54151736  
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 Http://www.100y.com.tw

IRL510, SiHL510

Vishay Siliconix

## Power MOSFET

PRODUCT SUMMARY		
$V_{DS}$ (V)	100	
$R_{DS(on)}$ ( $\Omega$ )	$V_{GS} = 5.0$ V	0.54
$Q_g$ (Max.) (nC)	6.1	
$Q_{gs}$ (nC)	2.6	
$Q_{gd}$ (nC)	3.3	
Configuration	Single	



### FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Logic-Level Gate Drive
- $R_{DS(on)}$  Specified at  $V_{GS} = 4$  V and 5 V
- 175 °C Operating Temperature
- Fast Switching
- Ease of Paralleling
- Lead (Pb)-free Available



RoHS\*  
COMPLIANT

### DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION	
Package	TO-220
Lead (Pb)-free	IRL510PbF SiHL510-E3
SnPb	IRL510 SiHL510

ABSOLUTE MAXIMUM RATINGS $T_C = 25$ °C, unless otherwise noted				
PARAMETER		SYMBOL	LIMIT	UNIT
Drain-Source Voltage		$V_{DS}$	100	V
Gate-Source Voltage		$V_{GS}$	$\pm 10$	
Continuous Drain Current	$V_{GS}$ at 5 V	$I_D$	$T_C = 25$ °C	A
			$T_C = 100$ °C	
Pulsed Drain Current <sup>a</sup>		$I_{DM}$	18	
Linear Derating Factor			0.29	W/°C
Single Pulse Avalanche Energy <sup>b</sup>		$E_{AS}$	100	mJ
Repetitive Avalanche Current <sup>a</sup>		$I_{AR}$	5.6	A
Repetitive Avalanche Energy <sup>a</sup>		$E_{AR}$	4.3	mJ
Maximum Power Dissipation	$T_C = 25$ °C	$P_D$	43	W
Peak Diode Recovery dV/dt <sup>c</sup>		dV/dt	5.5	V/ns
Operating Junction and Storage Temperature Range		$T_J, T_{stg}$	- 55 to + 175	°C
Soldering Recommendations (Peak Temperature)	for 10 s		300 <sup>d</sup>	
Mounting Torque	6-32 or M3 screw		10	
			1.1	N · m

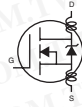

#### Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- $V_{DD} = 25$  V, starting  $T_J = 25$  °C,  $L = 4.8$  mH,  $R_G = 25$   $\Omega$ ,  $I_{AS} = 5.6$  A (see fig. 12).
- $I_{SD} \leq 5.6$  A,  $dI/dt \leq 75$  A/ $\mu$ s,  $V_{DD} \leq V_{DS}$ ,  $T_J \leq 175$  °C.
- 1.6 mm from case.

\* Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	$R_{thJA}$	-	62	°C/W
Case-to-Sink, Flat, Greased Surface	$R_{thCS}$	0.50	-	
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	3.5	

SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$ , unless otherwise noted							
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
<b>Static</b>							
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$		100	-	-	V
$V_{DS}$ Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25\text{ }^\circ\text{C}, I_D = 1\text{ mA}$		-	0.12	-	V/°C
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$		1.0	-	2.0	V
Gate-Source Leakage	$I_{GSS}$	$V_{GS} = \pm 10\text{ V}$		-	-	$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 100\text{ V}, V_{GS} = 0\text{ V}$		-	-	25	$\mu\text{A}$
		$V_{DS} = 80\text{ V}, V_{GS} = 0\text{ V}, T_J = 150\text{ }^\circ\text{C}$		-	-	250	
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 5.0\text{ V}$	$I_D = 3.4\text{ A}^b$	-	-	0.54	$\Omega$
		$V_{GS} = 4.0\text{ V}$	$I_D = 2.8\text{ A}^b$	-	-	0.76	
Forward Transconductance	$g_{fs}$	$V_{DS} = 50\text{ V}, I_D = 3.4\text{ A}^b$		1.9	-	-	S
<b>Dynamic</b>							
Input Capacitance	$C_{iss}$	$V_{GS} = 0\text{ V}, V_{DS} = 25\text{ V}, f = 1.0\text{ MHz}$ , see fig. 5		-	250	-	pF
Output Capacitance	$C_{oss}$			-	80	-	
Reverse Transfer Capacitance	$C_{rss}$			-	15	-	
Total Gate Charge	$Q_g$	$V_{GS} = 5.0\text{ V}$	$I_D = 5.6\text{ A}, V_{DS} = 80\text{ V}$ see fig. 6 and 13 <sup>b</sup>	-	-	6.1	nC
Gate-Source Charge	$Q_{gs}$			-	-	2.6	
Gate-Drain Charge	$Q_{gd}$			-	-	3.3	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 50\text{ V}, I_D = 5.6\text{ A}$ $R_G = 12\text{ }\Omega, R_D = 8.4\text{ }\Omega$ see fig. 10 <sup>b</sup>		-	9.3	-	ns
Rise Time	$t_r$			-	47	-	
Turn-Off Delay Time	$t_{d(off)}$			-	16	-	
Fall Time	$t_f$			-	18	-	
Internal Drain Inductance	$L_D$	Between lead, 6 mm (0.25") from package and center of die contact 		-	4.5	-	nH
Internal Source Inductance	$L_S$			-	7.5	-	
<b>Drain-Source Body Diode Characteristics</b>							
Continuous Source-Drain Diode Current	$I_S$	MOSFET symbol showing the integral reverse p - n junction diode 		-	-	5.6	A
Pulsed Diode Forward Current <sup>a</sup>	$I_{SM}$			-	-	18	
Body Diode Voltage	$V_{SD}$	$T_J = 25\text{ }^\circ\text{C}, I_S = 5.6\text{ A}, V_{GS} = 0\text{ V}^b$		-	-	2.5	V
Body Diode Reverse Recovery Time	$t_{rr}$	$T_J = 25\text{ }^\circ\text{C}, I_F = 5.6\text{ A}, di/dt = 100\text{ A}/\mu\text{s}^b$		-	110	130	ns
Body Diode Reverse Recovery Charge	$Q_{rr}$			-	0.50	0.65	$\mu\text{C}$
Forward Turn-On Time	$t_{on}$	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and $L_D$ )					

### Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- Pulse width  $\leq 300\text{ }\mu\text{s}$ ; duty cycle  $\leq 2\%$ .



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**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted

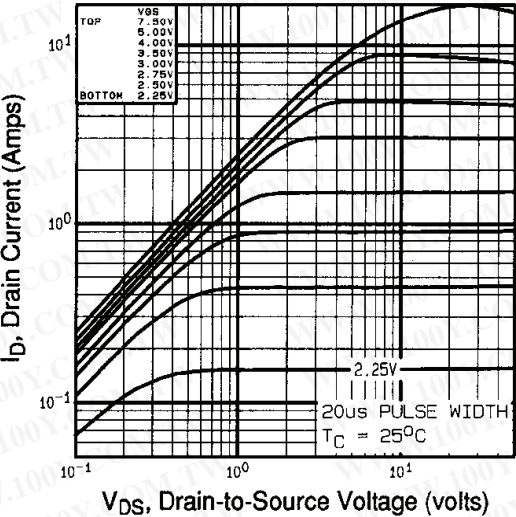


Fig. 1 - Typical Output Characteristics,  $T_C = 25^\circ\text{C}$

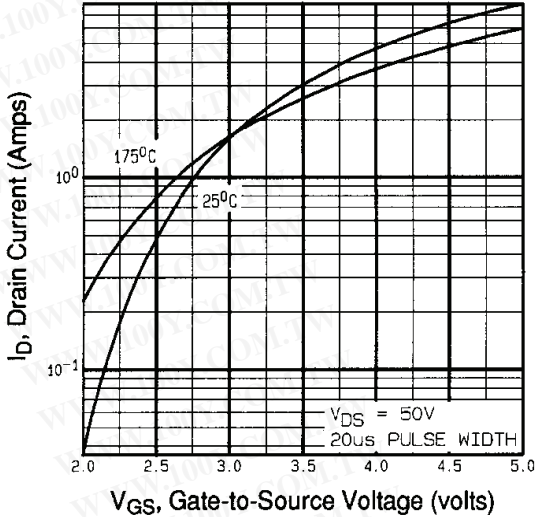


Fig. 3 - Typical Transfer Characteristics

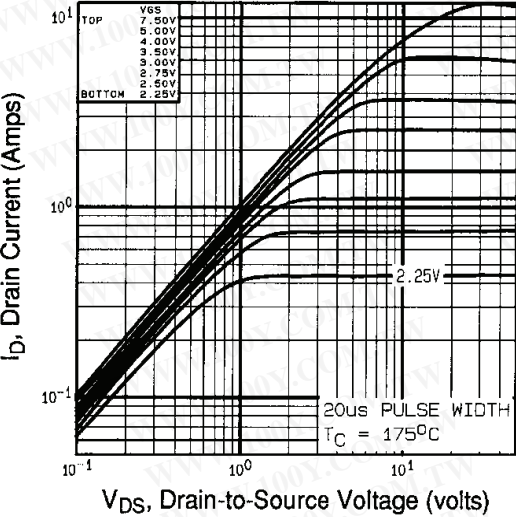


Fig. 2 - Typical Output Characteristics,  $T_C = 175^\circ\text{C}$

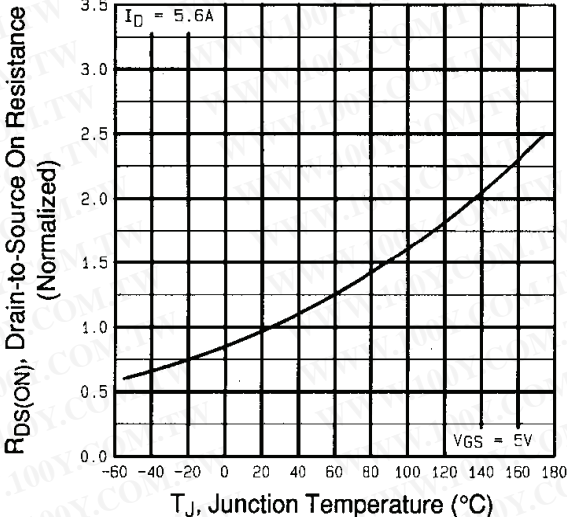


Fig. 4 - Normalized On-Resistance vs. Temperature

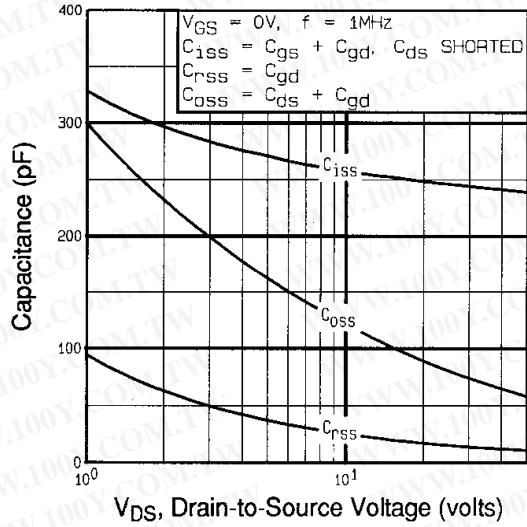


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

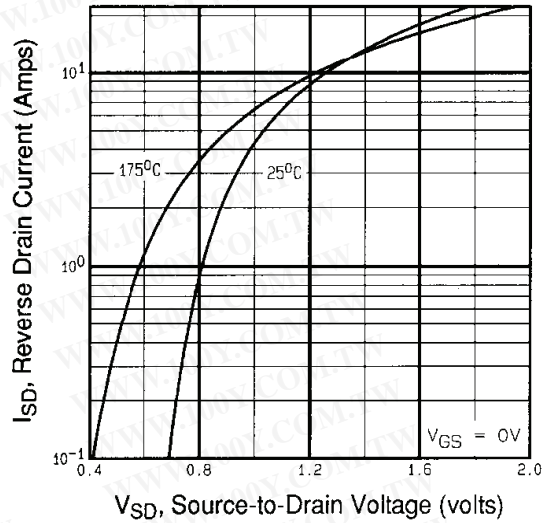


Fig. 7 - Typical Source-Drain Diode Forward Voltage

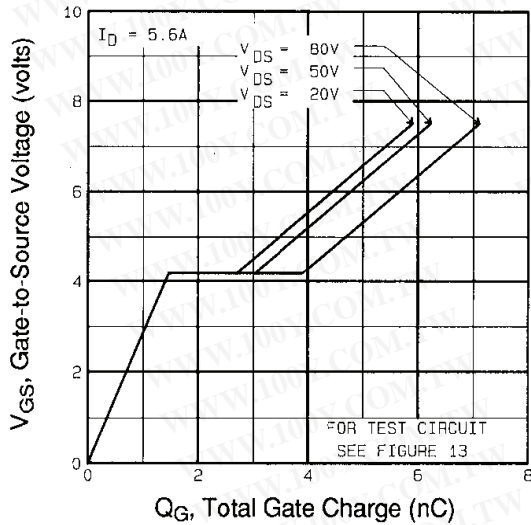


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

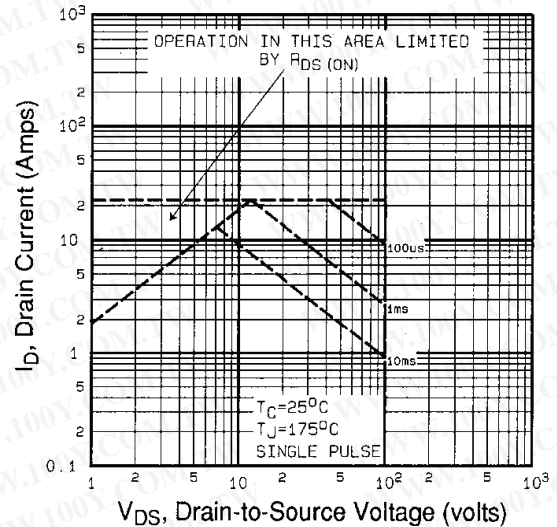
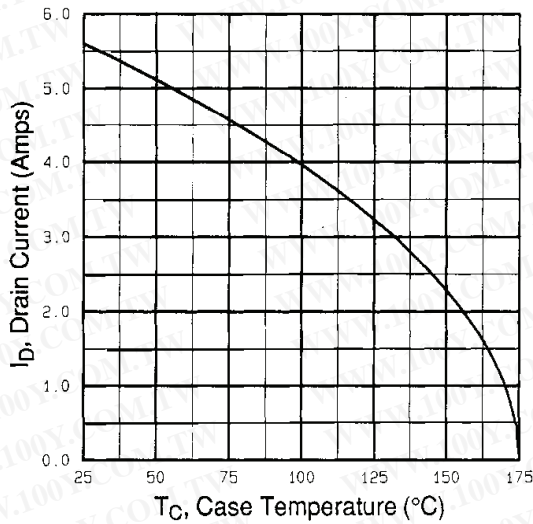
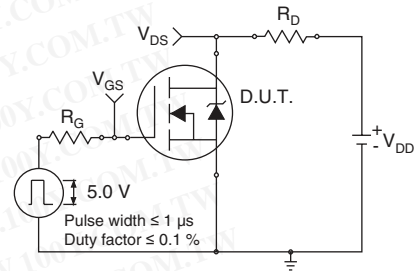


Fig. 8 - Maximum Safe Operating Area

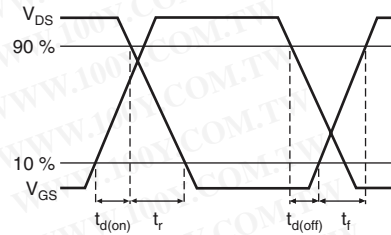




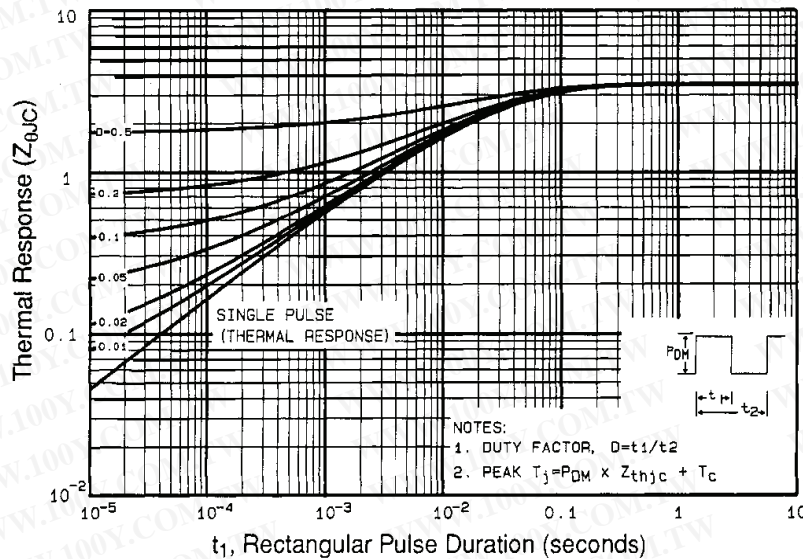
**Fig. 9 - Maximum Drain Current vs. Case Temperature**



**Fig. 10a - Switching Time Test Circuit**



**Fig. 10b - Switching Time Waveforms**



**Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case**

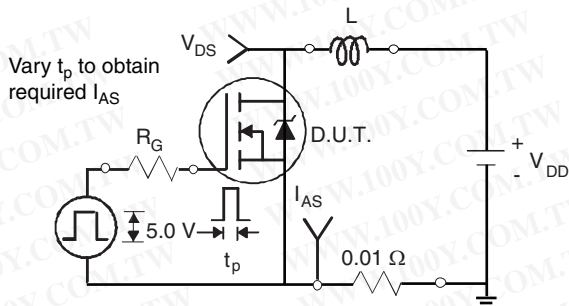


Fig. 12a - Unclamped Inductive Test Circuit

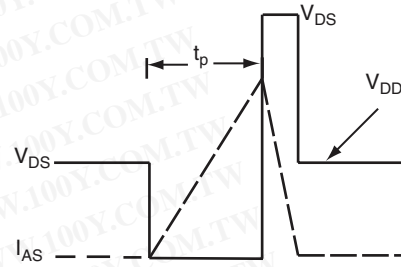


Fig. 12b - Unclamped Inductive Waveforms

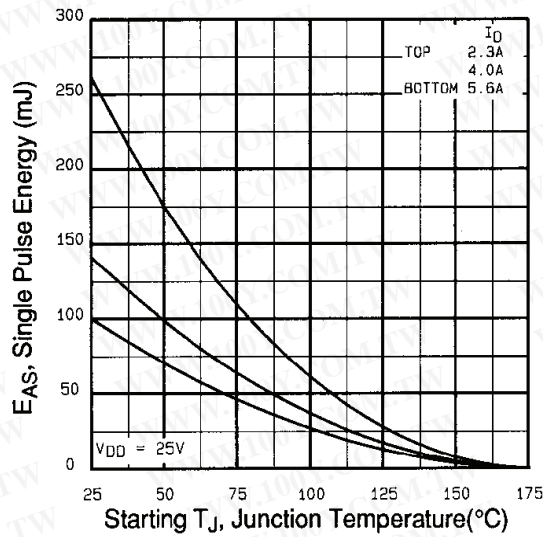


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

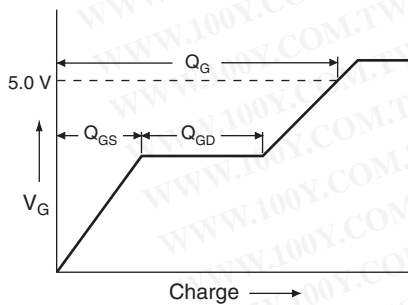


Fig. 13a - Basic Gate Charge Waveform

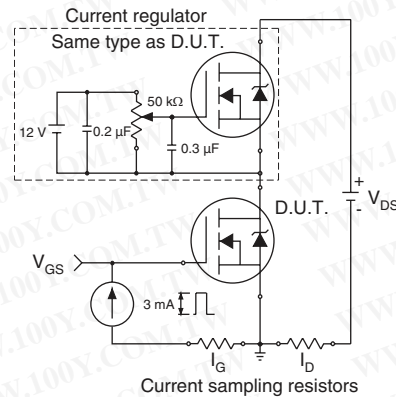
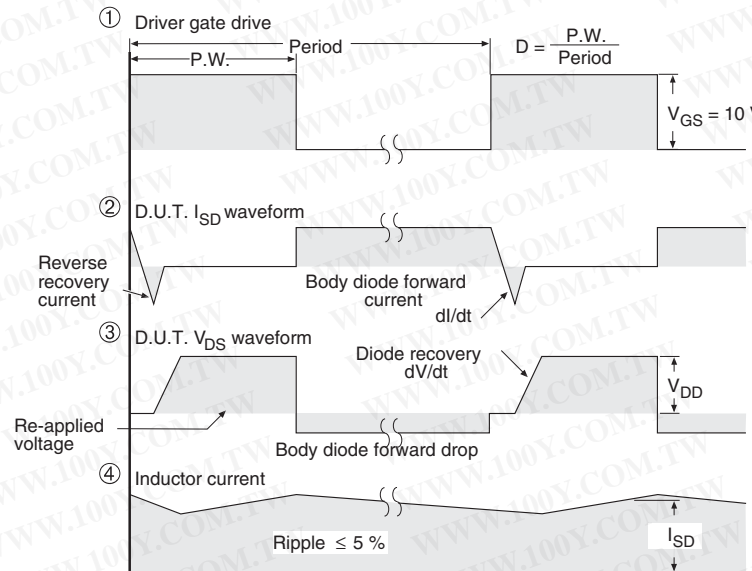
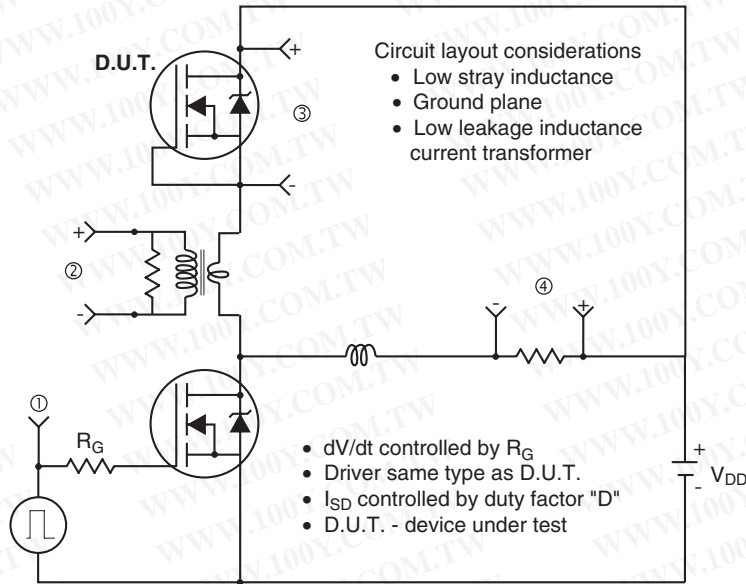


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery  $dV/dt$  Test Circuit



\*  $V_{GS} = 5 V$  for logic level devices

Fig. 14 - For N-Channel

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